

Photo Report on Test Setups

Report Reference: MDE_PEIKER_1801_FCC_Photo_Setups

Test Laboratory:

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Note:

The following test results relate only to the devices specified in this document. This report shall not be reproduced in parts without the written approval of the test laboratory.

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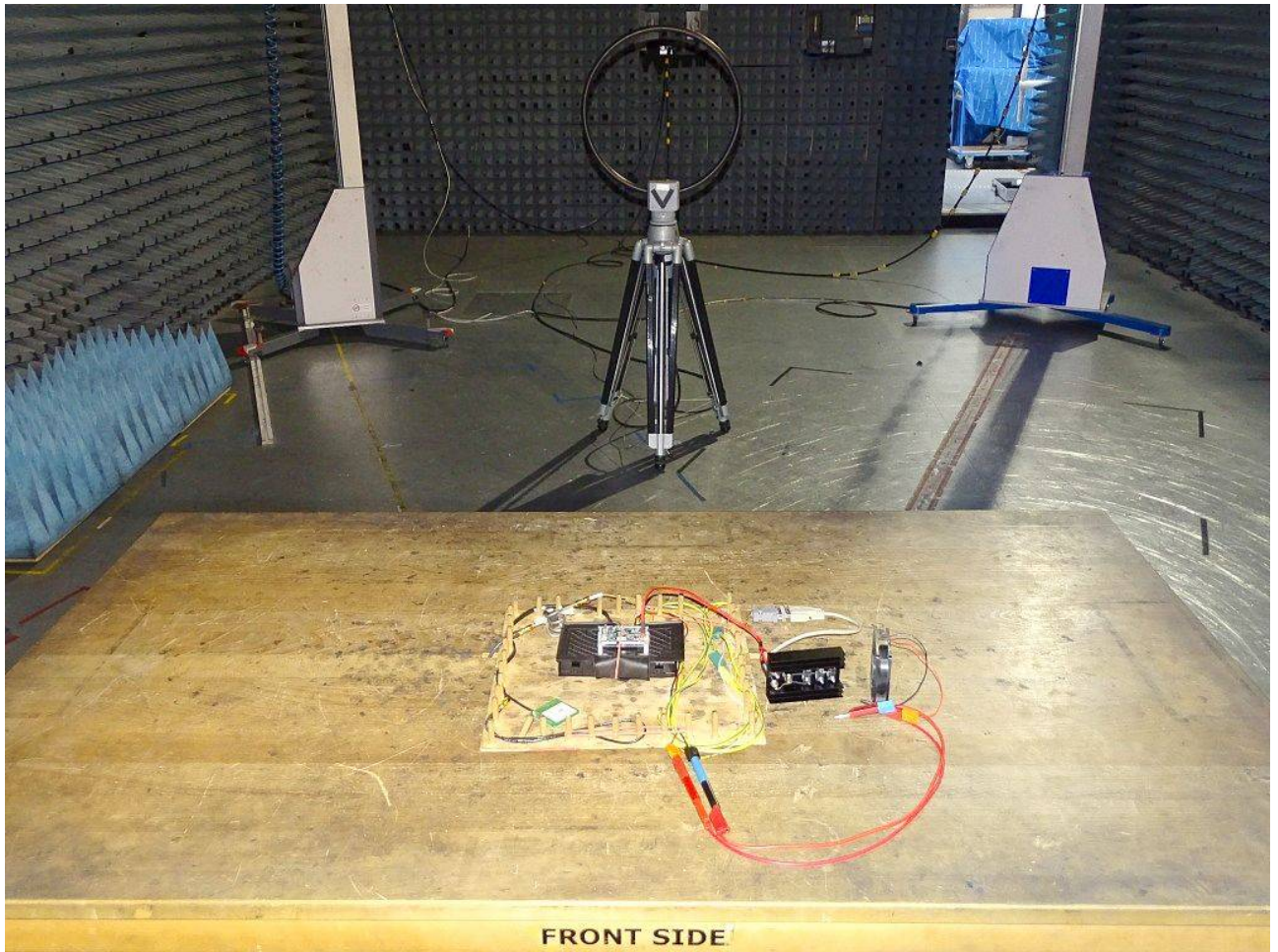


Photo 1: Test setup for radiated measurements (Enclosure, semi-anechoic chamber, 9 kHz to 30 MHz, intentional radiator §15, ANSI C63.10) EUT horizontal, WPT

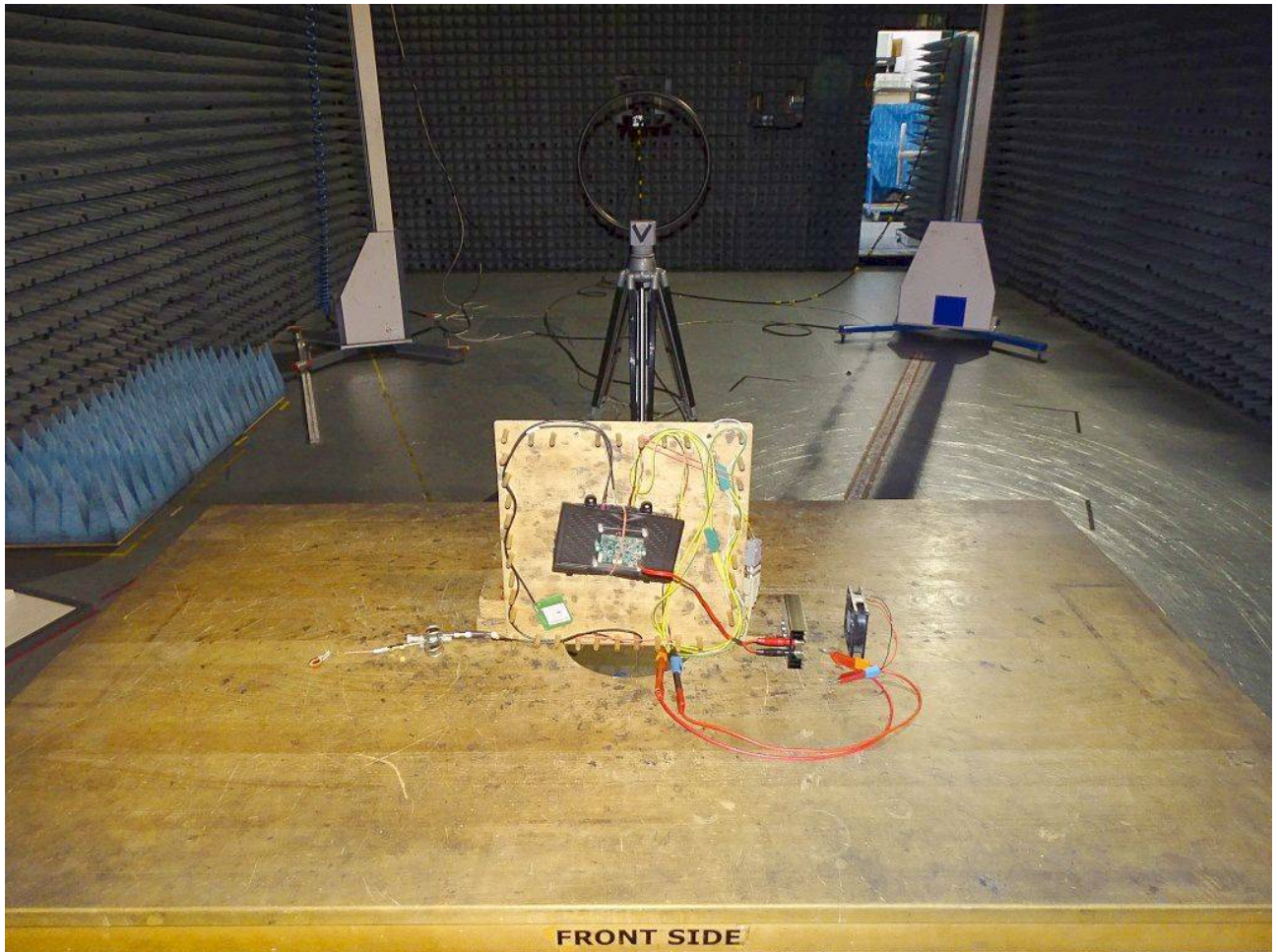


Photo 2: Test setup for radiated measurements (Enclosure, semi-anechoic chamber, 9 kHz to 30 MHz, intentional radiator §15, ANSI C63.10) EUT vertical, WPT

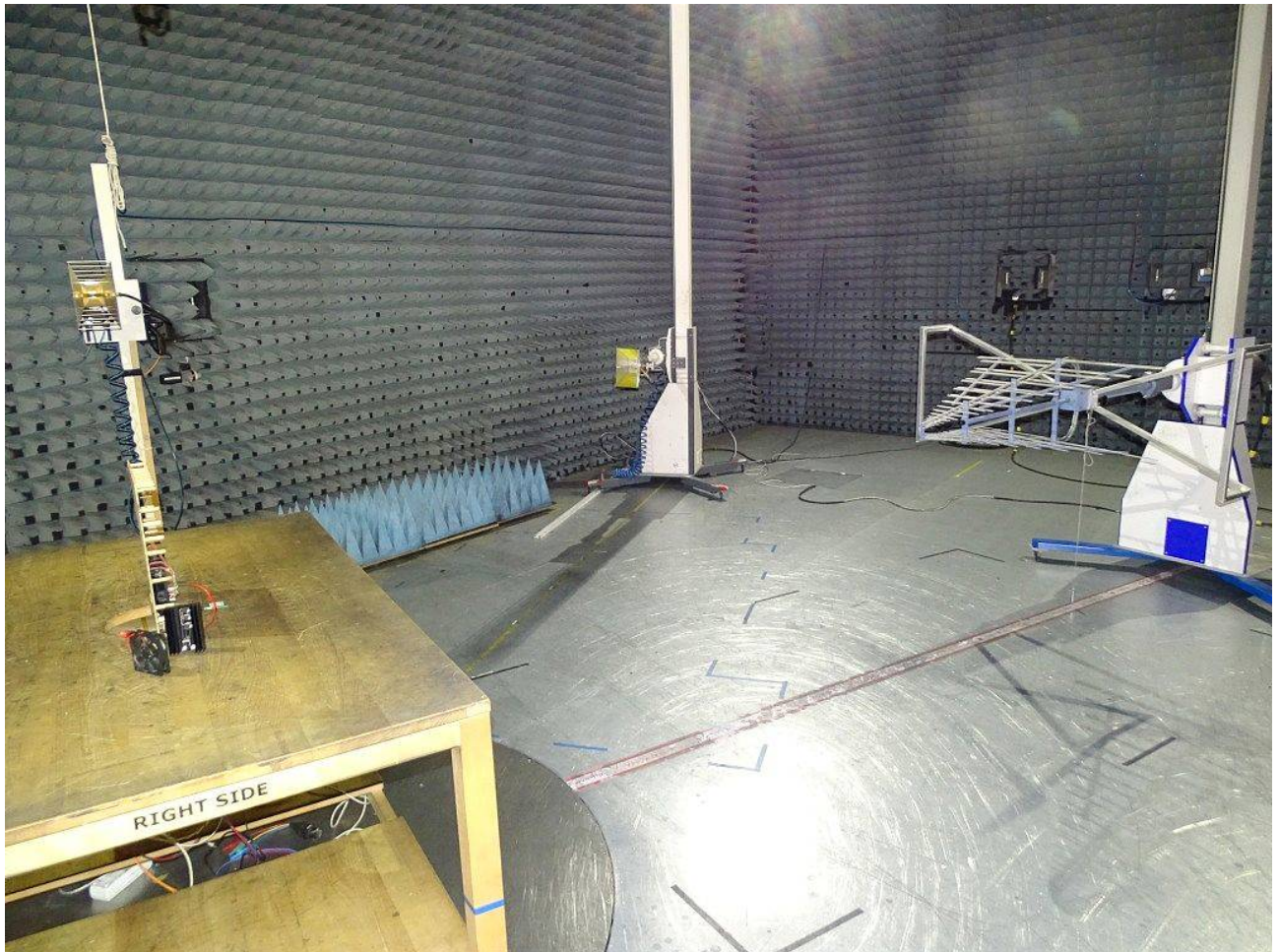


Photo 3: Test setup for radiated measurements (Enclosure, semi-anechoic chamber, 30 MHz to 1 GHz, intentional radiator §15, ANSI C63.10) WPT

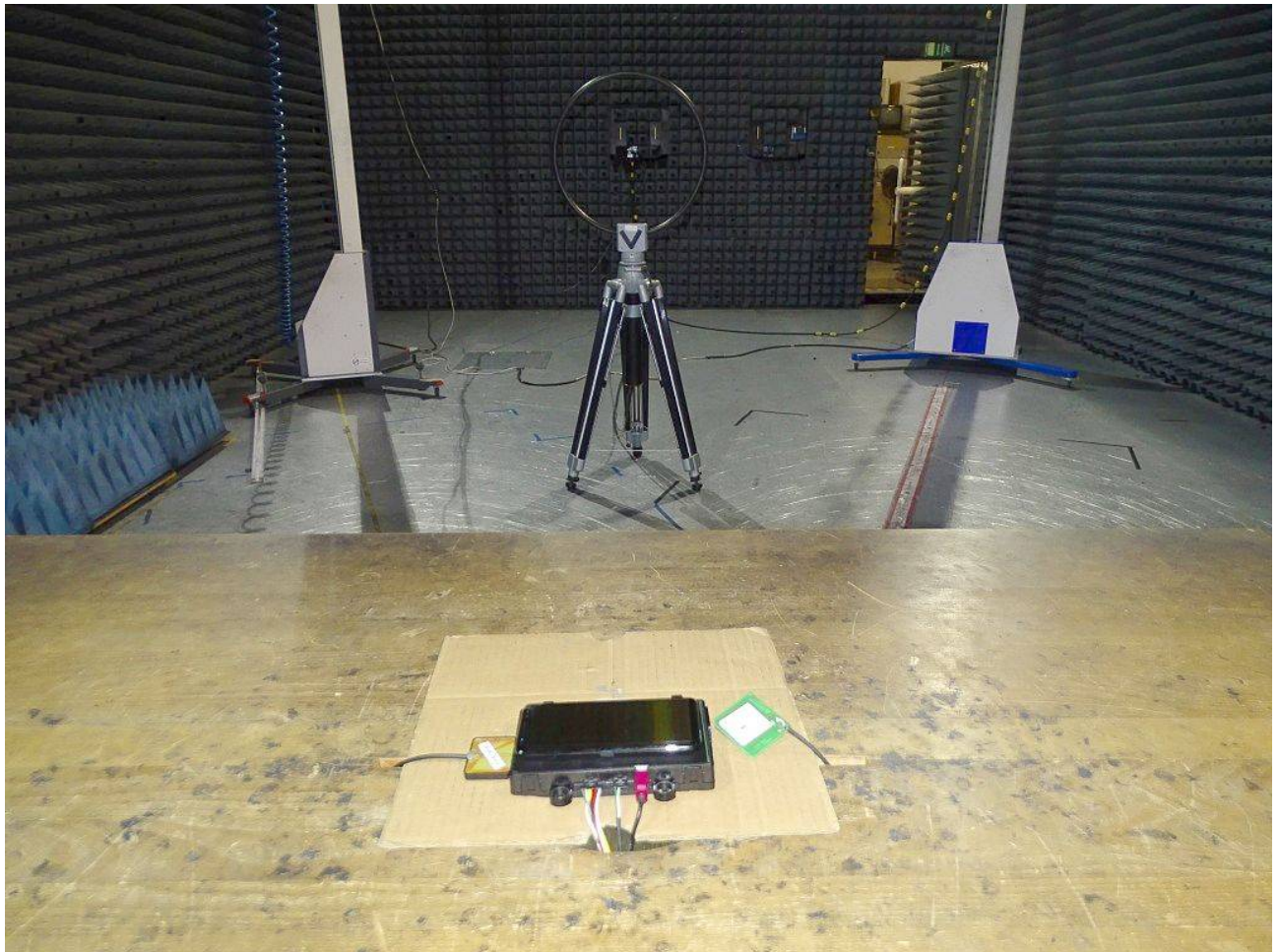


Photo 4: Test setup for radiated measurements (Enclosure, semi-anechoic chamber, 9 kHz to 30 MHz, intentional radiator §15, ANSI C63.10)
EUT horizontal, WPT
NFC, integral antenna

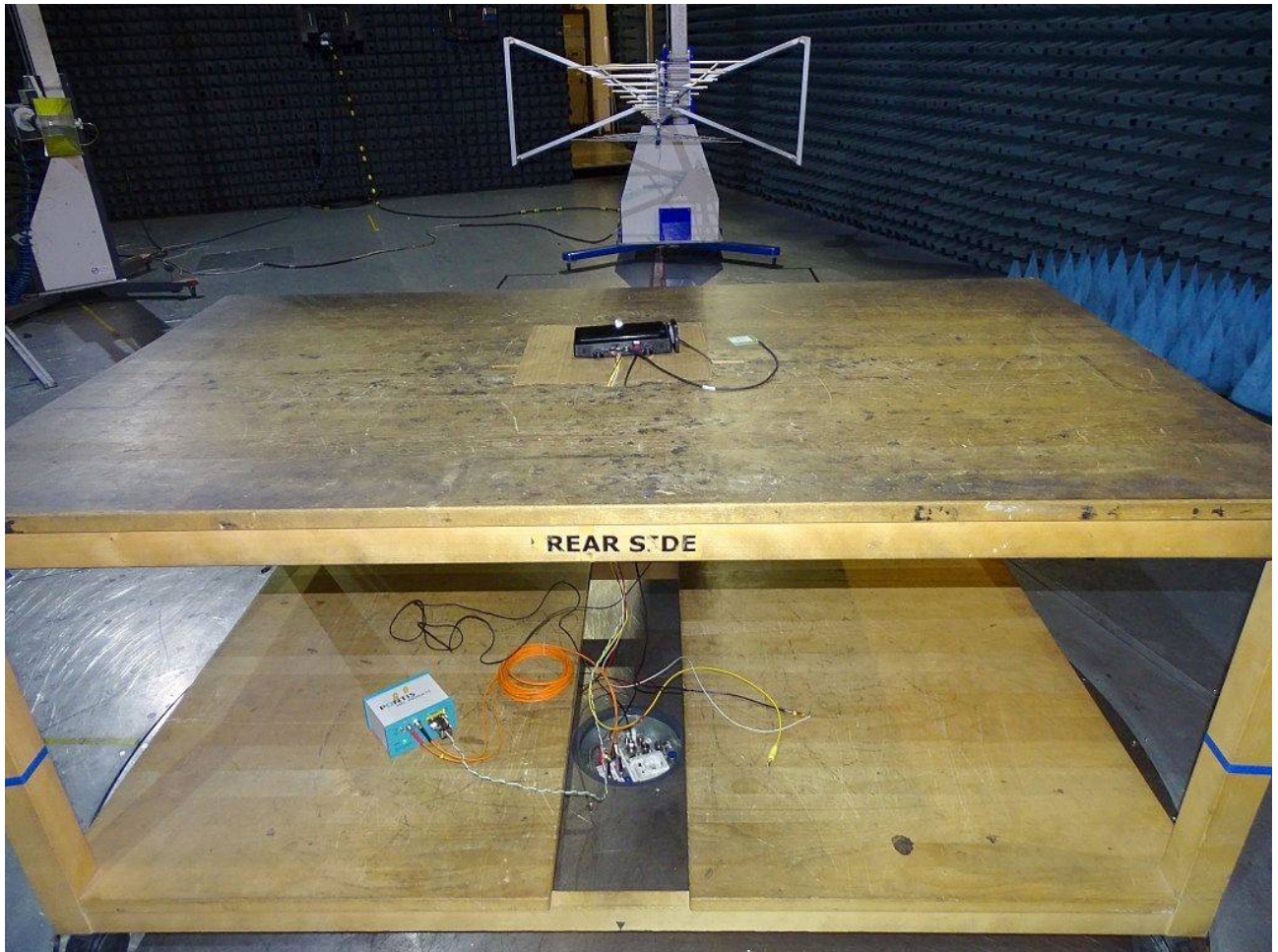


Photo 5: Test setup for radiated measurements (Enclosure, semi-anechoic chamber, 30 MHz to 1 GHz, intentional radiator §15, ANSI C63.10) NFC

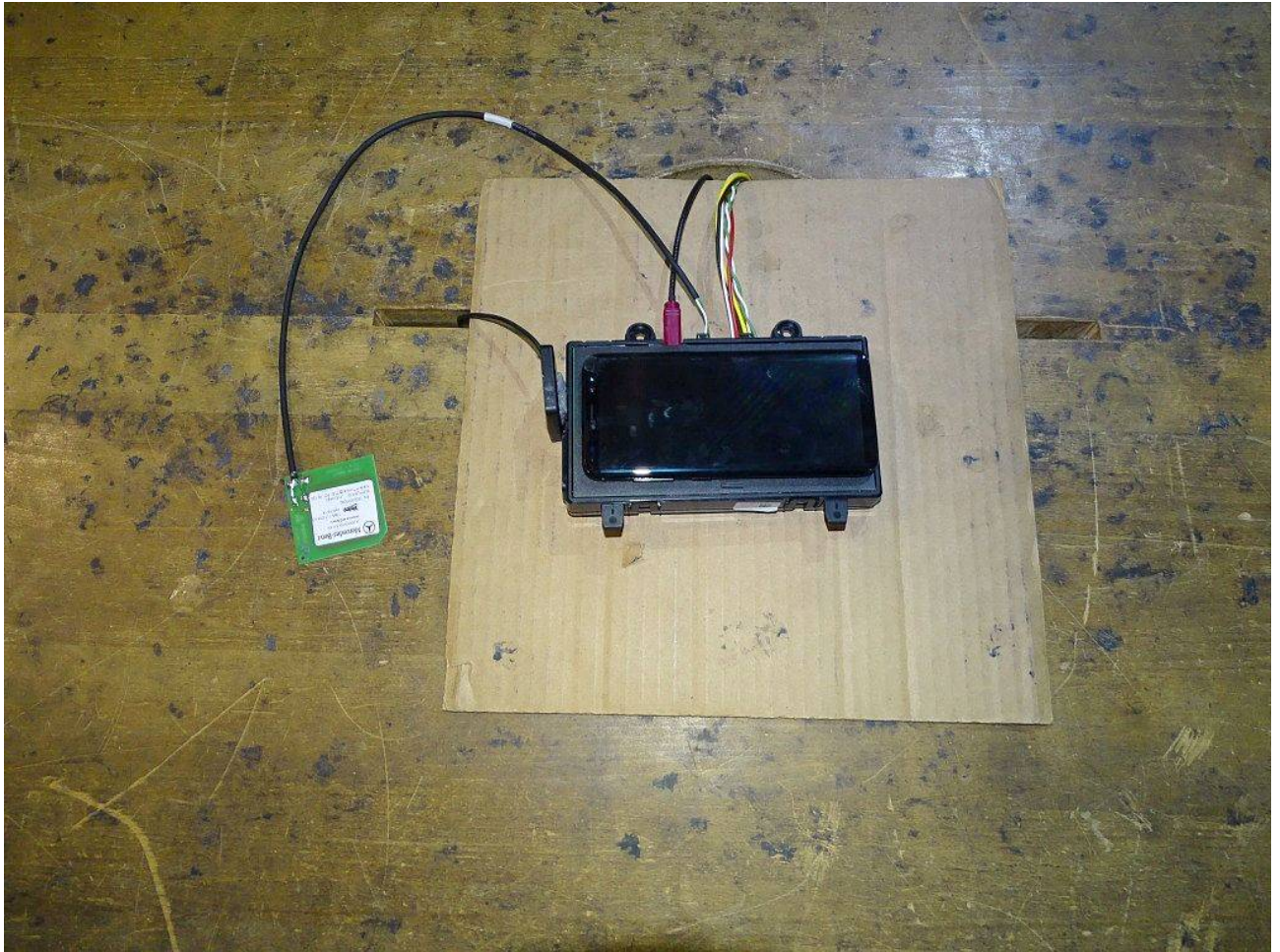


Photo 6: Test setup for radiated measurements (Enclosure, semi-anechoic chamber, NFC integral antenna, detail)



Photo 7: Test setup for radiated measurements (Enclosure, semi-anechoic chamber, NFC external antenna, detail)